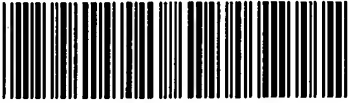


**Search Notes**

Application/Control No.

10/830,178

Examiner

Huy C. Ho

Applicant(s)/Patent under  
Reexamination

LEE ET AL.

Art Unit

2617

**SEARCHED**

Class	Subclass	Date	Examiner
370	338	3/22/2007	HH
	254	3/22/2007	HH
455	435.1	3/22/2007	HH
709	249	3/22/2007	HH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST image and keyword search in USPATConclusion, US-PGPUB, USOCR, EPO, JPO, DERWENT, IBM_TDB (See attached search strategy)	3/22/2007	HH